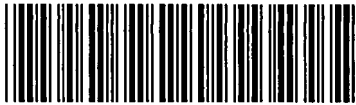


**Search Notes**

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Chuck Huynh

Applicant(s)/Patent under  
Reexamination

NAKAYAMA ET AL.

Art Unit

2617

**SEARCHED**

Class	Subclass	Date	Examiner
Updated	Search	6/19/2007	AX
455	411	6/19/2007	AX

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Class/Subclass	6/19/2007	AX
Combined Text Searched	6/19/2007	AX
Reviewed Prior Arts	6/19/07	AX